Jincheng Zheng

Education:

- Physics Department of National University of Singapore (SINGAPORE, 2002, PhD)
- Lawrence Berkeley National Laboratory (USA, 1999, Visiting Student)
- Physics Department of Xiamen University (CHINA, 1995, BA)

Research and Professional Experience:

- Assistant Materials Scientist, Condensed Matter Physics and Materials Science Department, Brookhaven National Laboratory, USA (May 2007 – present).
- Assistant Materials Scientist, Center for Functional Nanomaterials, Brookhaven National Laboratory, USA (Mar. 2006 – May 2007).
- Research Associate, Center for Functional Nanomaterials, Brookhaven National Laboratory, New York (USA, 2003 - 2006)
- Research Associate, Theory of Condensed Matter, The Cavendish Laboratory , University of Cambridge (UK, 2001 - 2002).
- Visiting Scholar, Chemistry Department, Yale University (USA, 2001).

Professional Activities:

Membership of professional organizations: Materials Science Society, American Physical Society, American Association for the Advancement of Science (AAAS).

Reviewer for international journals: Phys. Rev. Lett., Phys. Rev. B, J. Phys. Chem., Nanotechnology, J. Phys.: Cond. Matter, J. Phys.D., Surface and Interface Analysis, Int. J. Nanosci.

Selected Publications:

- X. Shen, P.B. Allen, J.T. Muckerman, J.W. Davenport, J.C. Zheng, Wire versus Tube: Stability of Small One Dimensional ZnO Nanostructures, Nano Lett., 7, 2267, (2007).
- R.F. Klie, J.C. Zheng, Y. Zhu, M. Varela, J. Wu and C. Leighton, Direct measurement of the low temperature spin-state transition in LaCoO3, Phys. Rev. Lett. 99, 047203, (2007).
- Y Zhu, JC Zheng, L Wu, AI Frenkel, J Hanson, P Northrup, W Ku, Nano-Scale disorder in $CaCu_3Ti_4O_{12}$: a new route to the enhanced dielectric response, Phys. Rev. Lett.99, 037602, (2007).
- J.C. Zheng, and Yimei Zhu, Searching for higher superconducting transition temperature in strained MgB2 using first principles calculations, Phys. Rev. B, 73,024509 (2006).
- J.-C. Zheng, L. Wu, Y. Zhu, and J.W. Davenport, On the sensitivity of electron and X-ray scattering factors to valence charge distribution, J. Appl. Cryst., 38, 648-656 (2005).